

Results of laser polishing using the field penetration experiment

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Laser polished samples

- Nb samples deposited as part of ARIES WP15 sent to RTU for laser polishing.
 - 3 Samples from STFC, and all 5 from Siegen. Samples deposited by INFN not sent as they had already been laser polished in the first test in the field penetration facility.
 - 3/5 STFC samples laser polished
- Samples have been returned, tested, analysed, and compared to the previous results.



Reminder

- DC magnetic field parallel to the surface
- Field local to the sample surface
 - Avoid edge effect.
 - Allow possibility if sample scanning.
- Magnetic field applied from one side of the sample to the opposing side, similar to an SRF cavity.
- Applied and penetrated field measured by Hall probe sensors
- 50×45 mm maximum, or a 50 mm diameter disk.





Effect of substrate polishing on B_{fp}

STFC	Siegen	INFN (with laser polishing sample surface)	
EP (224.7±8.5)	EP (177.0±6.1)		
		Tumbling (205.0±7.8)	
SUBU CERN (222.6±0.9)	SUBU INFN (169.9±5.1)	SUBU INFN (178.9±2.2)	
SUBU INFN (204.8±6.9)	SUBU CERN (159.7±1.4)	SUBU CERN (176.7±4.3)	
-	Tumbling (159.8±1.6)		
EP + SUBU (191.0±4.3)	EP + SUBU (134.2±1.1)	EP + SUBU (148.0±3.7)	

<u>Magnetic Field Penetration of Niobium Thin Films Produced by the ARIES Collaboration</u> – (Click link for SRF 21 poster) <u>Note:</u> These results were analysed using a different technique.

Note: The effect of polishing has slightly changed compared to previous report due to the change in analysis method



Laser treatment parameters

- All samples sent for laser polishing had the same parameters for treatment:
 - Wavelength: 1,063 mk
 - Intensity: 70 MW/cm²
 - Pulse duration: 6nm
 - Dose: 66 J/cm²
 - Step: 5 mk
 - Frequency: 10 Hz
 - Beam diameter: 3mm
- Samples treated:
 - STFC: C7 SUBU CERN, L13 EP, L18 EP + SUBU
 - Siegen: C1 SUBU CERN, L1 SUBU INFN, L10 EP, L23 EP + SUBU, L9 Tumbling
- Surface characterisation by Artur has been reported at the last IFAST meeting, and are shown again over the next few slides



30.0

0

50.0

90.0

Delta [,]

. .

130.0 nm

50.0

90.0 m

•









Siegen samples

• The solid lines and markers are pre laser polishing.

10

and a second second

140

120

100

80

60

40

20

0

B_{fp} [mT]

C1 - Siegen - 3μ m SUBU CERN L1 - Siegen - 3μ m SUBU INFN

L23 - Siegen - 3μ m EP+SUBU L9 - Siegen - 3μ m Tumbling

2

3

7

8

9

6

5

T [K]

L10 - Siegen - 3µm EP

• Dashed lines and empty markers are post laser polishing

Only the substrate polished by SUBU CERN benefitted from the laser polishing. The other 4 samples had a reduction in $B_{fp}(0 \text{ K})$.

C7 and L13 behave very similar after laser polishing

200

150

100

50

0

C7 - STFC - 10µm SUBU CERN

L18 - STFC - 10µm EP+SUBU

2

3

4

5

T [K]

7

6

8

9

10

L13 - STFC - $10\mu m EP$

B_{fp} [mT]



STFC samples

- The solid lines and markers are pre laser polishing.
- Dashed lines and empty markers are post laser polishing

All of the STFC samples saw an increase in $B_{fp}(0 \text{ K})$. Both EP and SUBU CERN polished substrates are almost identical (0.1 mT difference).

- Is this optimum performance for B_{fp} of 10µm of Nb?
- Perhaps this is a way to improve bulk Nb cavities?



Effect of laser polishing the Nb

STFC	Siegen	INFN (with laser polishing sample surface)	
SUBU CERN (234.9 ± 1.3)	SUBU CERN (152.7 ± 2.5)	Tumbling (205.0 ± 7.8)	Largest B _{fp} (0 K)
EP (234.8 ± 2.4)	SUBU INFN (150.1 ± 2.1)	SUBU INFN (178.9 ± 2.2)	
	Tumbling (125.4 ± 0.9)	SUBU CERN (176.7 ± 4.3)	
	EP + SUBU (125.3 ± 2.1)		
EP + SUBU (198.1 ± 6.0)	EP (121.4 ± 2.1)	EP + SUBU (148.0 ± 3.7)	Lowest B _{fp} (0 K)

<u>Note:</u> Samples deposited at INFN only underwent 1 round of laser polishing, so the data in this table is the same as first – Just here for comparison.

Full comparison



STFC	Siegen	INFN	
SUBU CERN + LP (234.9)	EP (177.0)	Tumbling + LP (205.0)	Largest B _{fp} (0 K)
EP + LP (234.8)	SUBU CERN + LP (152.7)	SUBU INFN + LP(178.9)	
EP (224.7)	SUBU INFN (169.9)	SUBU CERN + LP(176.7)	
SUBU CERN (222.6)	SUBU CERN (159.7)	EP + SUBU + LP (148.0)	
SUBU INFN (204.8)	Tumbling (159.8)		
EP + SUBU + LP (198.1)	SUBU INFN + LP(150.1)		
EP + SUBU (191.0)	EP + SUBU (134.2)		
	Tumbling + LP (125.4)		
	EP + SUBU + LP (125.3)		
	EP + LP (121.4)		Lowest B _{fp} (0 K)

<u>Note</u>: There are differences between each institute such as sample thickness, therefore each institute must be compared individually.



Conclusion

- Laser polishing increased the performance for the samples deposited at STFC, and the SUBU CERN sample deposited at Siegen.
- Reduction in field penetration performance in the samples deposited at Siegen.
- Reza currently has the laser treated samples from STFC and Siegen for surface analysis.
- Questions to Artur:
 - Was the laser polishing consistent for each sample? Any change in intensity or time taken etc? This information is now included in the presentation
 - Have you performed surface characterisation on these samples?
 - Surface after irradiation is in Artur's previous IFAST (3rd) presentation, which includes AFM and optical images
 - Would you like these samples returned once Reza has finished?

Everyone: Should I begin a draft of this paper? Would be beneficial?



Thank you for your attention, I am happy to answer any questions.





Results comparison

				Results from Bratislava VSM					Field penetration experiment								
				Pre laser polishing			Post lase	Post laser polishing			First test			Second test - post laser polishing			
Origin	Material	Thickness	Substrate Treatment	Bperp(4.2 K) [mT]	Bpara(4.2 K) [mT]	Tc(5 mT) [K]	Bperp(4.2 K)[mT]	Bpara(4.2 K) [mT]	Tc (K)	ΔТс (К)	Bfp(0 K) (mT)	ΔBfp(0 K) (mT)	Тс (К)	∆Тс (К)	Bfp(0 K) (mT)	ΔBfp(0 K) (mT)	
STFC	Nb	10µm	SUBU CERN	24.1	150.1	9.35	0	0	9.2	0.3	222.6	0.9	9.17	0.04	234.90	1.10	
STFC	Nb	10µm	EP	22	100.3	9.35	0	0	9.6	0.4	224.7	8.5	9.19	0.09	234.80	2.40	
STFC	Nb	10µm	EP + SUBU	17.7	61	9.3	0	0	9.3	0.3	191.0	4.3	9.55	0.29	198.10	6.00	
STFC	Nb	10µm	SUBU INFN	17.3	73.2	9.2	0	0	9.3	0.4	204.8	6.9					
Siegen	Nb	3µm	SUBU CERN	15.5	49.6	9.5	0	0	9.4	0.3	159.7	1.4	9.24	0.13	172.70	2.50	
Siegen	Nb	3µm	SUBU INFN	14.5	38	9.6	0	0	9.7	0.4	169.9	5.1	9.75	0.14	150.10	2.10	
Siegen	Nb	3µm	Tumbling	16	38.6	9.38	0	0	9.1	0.2	159.8	1.6	8.92	0.06	125.40	0.90	
Siegen	Nb	3µm	EP	15.5	32.7	9.38	0	0	9.6	0.4	177.0	6.1	8.98	0.15	121.43	2.10	
Siegen	Nb	3µm	EP + SUBU	15	24.5	9.38	0	0	9.0	0.3	134.2	1.1	8.90	0.15	125.30	2.10	
INFN	Nb	3µm	SUBU5 CERN	12	0	9.37	17	50.2	9.3	0.3	176.7	4.3					
INFN	Nb	3µm	Tumbling	18	0	9.48	19.1	42.5	9.7	0.4	205.0	7.8					
INFN	Nb	3µm	EP + SUBU5	14	0	9.37	15.5	47.2	9.2	0.3	148.0	3.7					
INFN	Nb	3µm	SUBU5 INFN	20	0	9.58	23.7	45	9.4	0.3	178.9	2.2					
INFN	Nb	3µm	EP	18	0	9.28	18.8	45.2	0.0	0.0	0.0	0.0					



STFC Samples, Pre – Laser treatment



20



Siegen samples, pre laser treatment





LNL samples, 1 round of laser treatment





STFC Samples, Post – Laser treatment





Siegen samples, post laser treatment

